Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,355	MATHIEU ET AL.	
Examiner	Art Unit	

Edwin A. León

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Class	Subclass	Date	Examiner
439	66	3/11/2005	EAL
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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